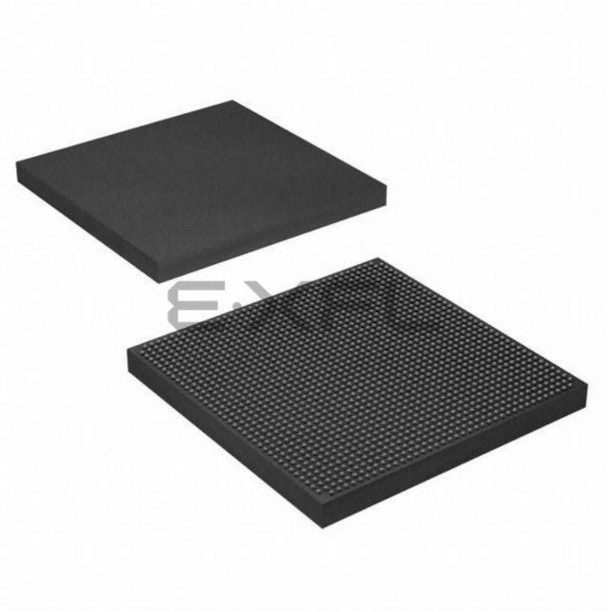
Intel - 5SGXMB5R1F40C2LN Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	41984000
Number of I/O	432
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-FBGA (40x40)
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxmb5r1f40c2ln

Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering (1), (2), (3) (Part 2 of 2)

Transceiver Speed Grade	Core Speed Grade							
	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L	I3YY	I4
3 GX channel—8.5 Gbps	—	Yes	Yes	Yes	—	Yes	Yes (4)	Yes

Notes to Table 1:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

(3) C2L, I2L, and I3L speed grades are for low-power devices.

(4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices.

Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering (1), (2)

Transceiver Speed Grade	Core Speed Grade			
	C1	C2	I2	I3
2 GX channel—12.5 Gbps GT channel—28.05 Gbps	Yes	Yes	—	—
3 GX channel—12.5 Gbps GT channel—25.78 Gbps	Yes	Yes	Yes	Yes

Notes to Table 2:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

CAUTION

Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 1 of 2)

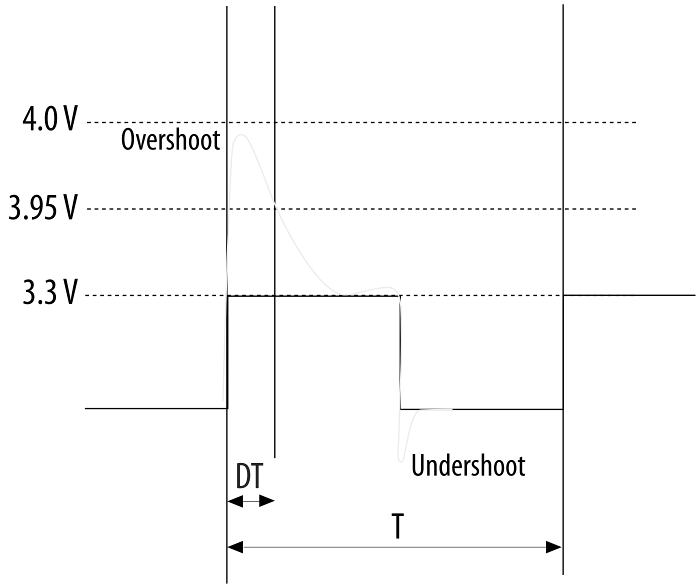
Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Power supply for core voltage and periphery circuitry	–0.5	1.35	V
V_{CCPT}	Power supply for programmable power technology	–0.5	1.8	V
V_{CCPGM}	Power supply for configuration pins	–0.5	3.9	V
V_{CC_AUX}	Auxiliary supply for the programmable power technology	–0.5	3.4	V
V_{CCBAT}	Battery back-up power supply for design security volatile key register	–0.5	3.9	V
V_{CCPD}	I/O pre-driver power supply	–0.5	3.9	V
V_{CCIO}	I/O power supply	–0.5	3.9	V

Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

Table 5. Maximum Allowed Overshoot During Transitions

Symbol	Description	Condition (V)	Overshoot Duration as % @ T_J = 100°C	Unit
Vi (AC)	AC input voltage	3.8	100	%
		3.85	64	%
		3.9	36	%
		3.95	21	%
		4	12	%
		4.05	7	%
		4.1	4	%
		4.15	2	%
		4.2	1	%

Figure 1. Stratix V Device Overshoot Duration



I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9. I/O Pin Leakage Current for Stratix V Devices (1)

Symbol	Description	Conditions	Min	Typ	Max	Unit
I_I	Input pin	V_I = 0 V to $V_{CCIOMAX}$	–30	—	30	µA
I_{OZ}	Tri-stated I/O pin	V_O = 0 V to $V_{CCIOMAX}$	–30	—	30	µA

Note to Table 9:

(1) If $V_O = V_{CCIO}$ to $V_{CCIOMax}$, 100 µA of leakage current per I/O is expected.

Bus Hold Specifications

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

Parameter	Symbol	Conditions	V_{CCIO}										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I_{SUSL}	$V_{IN} > V_{IL}$ (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	µA
High sustaining current	I_{SUSH}	$V_{IN} < V_{IH}$ (minimum)	–22.5	—	–25.0	—	–30.0	—	–50.0	—	–70.0	—	µA
Low overdrive current	I_{ODL}	$0V < V_{IN} < V_{CCIO}$	—	120	—	160	—	200	—	300	—	500	µA
High overdrive current	I_{ODH}	$0V < V_{IN} < V_{CCIO}$	—	–120	—	–160	—	–200	—	–300	—	–500	µA
Bus-hold trip point	V_{TRIP}	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices (1) (Part 1 of 2)

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3, I3YY	C4,I4	
25-Ω R_S	Internal series termination with calibration (25-Ω setting)	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±30	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±35	±35	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCPD} = 2.5 V	±25	±25	±25	±25	%

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices *(1), (2), (3), (4), (5), (6)*

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1:

(1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.
(2) R_{SCAL} is the OCT resistance value at power-up.
(3) ΔT is the variation of temperature with respect to the temperature at power-up.
(4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
(5) dR/dT is the percentage change of R_{SCAL} with temperature.
(6) dR/dV is the percentage change of R_{SCAL} with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) *(1)*

Symbol	Description	V_{CCIO} (V)	Typical	Unit
dR/dV	OCT variation with voltage without recalibration	3.0	0.0297	%/mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 2 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{ol} (mA)	I_{oh} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
HSTL-18 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	–8
HSTL-18 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	–16
HSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	–8
HSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	–16
HSTL-12 Class I	–0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25 * V_{CCIO}$	$0.75 * V_{CCIO}$	8	–8
HSTL-12 Class II	–0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25 * V_{CCIO}$	$0.75 * V_{CCIO}$	16	–16
HSUL-12	—	$V_{REF} - 0.13$	$V_{REF} + 0.13$	—	$V_{REF} - 0.22$	$V_{REF} + 0.22$	$0.1 * V_{CCIO}$	$0.9 * V_{CCIO}$	—	—

Table 20. Differential SSTL I/O Standards for Stratix V Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	$V_{CCIO} + 0.6$	$V_{CCIO}/2 - 0.2$	—	$V_{CCIO}/2 + 0.2$	0.62	$V_{CCIO} + 0.6$
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	$V_{CCIO} + 0.6$	$V_{CCIO}/2 - 0.175$	—	$V_{CCIO}/2 + 0.175$	0.5	$V_{CCIO} + 0.6$
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	*(1)*	$V_{CCIO}/2 - 0.15$	—	$V_{CCIO}/2 + 0.15$	0.35	—
SSTL-135 Class I, II	1.283	1.35	1.45	0.2	*(1)*	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$
SSTL-125 Class I, II	1.19	1.25	1.31	0.18	*(1)*	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	—
SSTL-12 Class I, II	1.14	1.2	1.26	0.18	—	$V_{REF} -0.15$	$V_{CCIO}/2$	$V_{REF} + 0.15$	–0.30	0.30

Note to Table 20:

(1) The maximum value for $V_{SWING(DC)}$ is not defined. However, each single-ended signal needs to be within the respective single-ended limits ($V_{IH(DC)}$ and $V_{IL(DC)}$).

Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 1 of 2)

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—

Table 23. Transceiver Specifications for Stratix V GX and GS Devices *(1)* **(Part 4 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors *(21)*	85–Ω setting	—	85 ± 30%	—	—	85 ± 30%	—	—	85 ± 30%	—	Ω
	100–Ω setting	—	100 ± 30%	—	—	100 ± 30%	—	—	100 ± 30%	—	Ω
	120–Ω setting	—	120 ± 30%	—	—	120 ± 30%	—	—	120 ± 30%	—	Ω
	150-Ω setting	—	150 ± 30%	—	—	150 ± 30%	—	—	150 ± 30%	—	Ω
V_{ICM} (AC and DC coupled)	V_{CCR_GXB} = 0.85 V or 0.9 V full bandwidth	—	600	—	—	600	—	—	600	—	mV
	V_{CCR_GXB} = 0.85 V or 0.9 V half bandwidth	—	600	—	—	600	—	—	600	—	mV
	V_{CCR_GXB} = 1.0 V/1.05 V full bandwidth	—	700	—	—	700	—	—	700	—	mV
	V_{CCR_GXB} = 1.0 V half bandwidth	—	750	—	—	750	—	—	750	—	mV
t_{LTR} *(11)*	—	—	—	10	—	—	10	—	—	10	µs
t_{LTD} *(12)*	—	4	—	—	4	—	—	4	—	—	µs
t_{LTD_manual} *(13)*	—	4	—	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$ *(14)*	—	15	—	—	15	—	—	15	—	—	µs
Run Length	—	—	—	200	—	—	200	—	—	200	UI
Programmable equalization (AC Gain) *(10)*	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)	—	—	16	—	—	16	—	—	16	dB

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) *(1)*

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	**Typ**	**Max**	**Min**	**Typ**	**Max**	
Reference Clock								
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL						
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS						
Input Reference Clock Frequency (CMU PLL) *(6)*	—	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) *(6)*	—	100	—	710	100	—	710	MHz
Rise time	20% to 80%	—	—	400	—	—	400	ps
Fall time	80% to 20%	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to –0.5	—	—	0 to –0.5	—	%
On-chip termination resistors *(19)*	—	—	100	—	—	100	—	Ω
Absolute V_{MAX} *(3)*	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	
Absolute V_{MIN}	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
V_{ICM} (AC coupled)	Dedicated reference clock pin	1050/1000 *(2)*			1050/1000 *(2)*			mV
	RX reference clock pin	1.0/0.9/0.85 *(22)*			1.0/0.9/0.85 *(22)*			V
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5) *(1)*

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors *(7)*	GT channels	—	100	—	—	100	—	Ω
Differential on-chip termination resistors for GX channels *(19)*	85-Ω setting	—	85 ± 30%	—	—	85 ± 30%	—	Ω
	100-Ω setting	—	100 ± 30%	—	—	100 ± 30%	—	Ω
	120-Ω setting	—	120 ± 30%	—	—	120 ± 30%	—	Ω
	150-Ω setting	—	150 ± 30%	—	—	150 ± 30%	—	Ω
V_{ICM} (AC coupled)	GT channels	—	650	—	—	650	—	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 0.85 V or 0.9 V	—	600	—	—	600	—	mV
	VCCR_GXB = 1.0 V full bandwidth	—	700	—	—	700	—	mV
	VCCR_GXB = 1.0 V half bandwidth	—	750	—	—	750	—	mV
t_{LTR} *(9)*	—	—	—	10	—	—	10	µs
t_{LTD} *(10)*	—	4	—	—	4	—	—	µs
t_{LTD_manual} *(11)*	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$ *(12)*	—	15	—	—	15	—	—	µs
Run Length	GT channels	—	—	72	—	—	72	CID
	GX channels	*(8)*						
CDR PPM	GT channels	—	—	1000	—	—	1000	± PPM
	GX channels	*(8)*						
Programmable equalization (AC Gain) *(5)*	GT channels	—	—	14	—	—	14	dB
	GX channels	*(8)*						
Programmable DC gain *(6)*	GT channels	—	—	7.5	—	—	7.5	dB
	GX channels	*(8)*						
Differential on-chip termination resistors *(7)*	GT channels	—	100	—	—	100	—	Ω
Transmitter								
Supported I/O Standards	—	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	—	8500	600	—	8500	Mbps
Data rate (10G PCS)	GX channels	600	—	12,500	600	—	12,500	Mbps

Figure 4 shows the differential transmitter output waveform.

Figure 4. Differential Transmitter/Receiver Output/Input Waveform

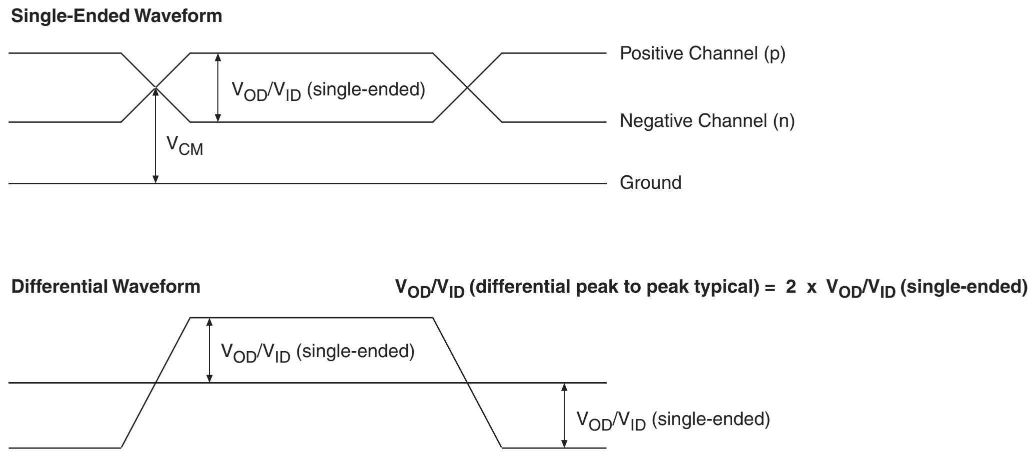


Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

Table 33. Memory Block Performance Specifications for Stratix V Devices (1), (2) (Part 2 of 2)

Memory	Mode	Resources Used		Performance							Unit
		ALUTs	Memory	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L, I3YY	I4	
M20K Block	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port with the read-during-write option set to **Old Data**, all supported widths	0	1	525	525	455	400	525	455	400	MHz
	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz

Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50%** output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F_{MAX}.

(3) The F_{MAX} specification is only achievable with Fitter options, **MLAB Implementation In 16-Bit Deep Mode** enabled.

Temperature Sensing Diode Specifications

Table 34 lists the internal TSD specification.

Table 34. Internal Temperature Sensing Diode Specification

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
–40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Table 35. External Temperature Sensing Diode Specifications for Stratix V Devices

Description	Min	Typ	Max	Unit
I_{bias}, diode source current	8	—	200	μA
$V_{bias,}$ voltage across diode	0.3	—	0.9	V
Series resistance	—	—	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	—

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 1 of 4)

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK_in} (input clock frequency) True Differential I/O Standards	Clock boost factor W = 1 to 40 *(4)*	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards *(3)*	Clock boost factor W = 1 to 40 *(4)*	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 *(4)*	5	—	520	5	—	520	5	—	420	5	—	420	MHz
f_{HSCLK_OUT} (output clock frequency)	—	5	—	800	5	—	800	5	—	625 *(5)*	5	—	525 *(5)*	MHz

Table 36. High-Speed I/O Specifications for Stratix V Devices *(1), (2)* (Part 2 of 4)

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Transmitter														
True Differential I/O Standards - f_{HSDR} (data rate)	SERDES factor J = 3 to 10 *(9), (11), (12), (13), (14), (15), (16)*	*(6)*	—	1600	*(6)*	—	1434	*(6)*	—	1250	*(6)*	—	1050	Mbps
	SERDES factor J ≥ 4 LVDS TX with DPA *(12), (14), (15), (16)*	*(6)*	—	1600	*(6)*	—	1600	*(6)*	—	1600	*(6)*	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps
	SERDES factor J = 1, uses SDR Register	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f_{HSDR} (data rate) *(10)*	SERDES factor J = 4 to 10 *(17)*	*(6)*	—	1100	*(6)*	—	1100	*(6)*	—	840	*(6)*	—	840	Mbps
$t_{x\ Jitter}$ - True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	160	—	—	160	—	—	160	—	—	160	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
$t_{x\ Jitter}$ - Emulated Differential I/O Standards with Three External Output Resistor Network	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	300	—	—	300	—	—	300	—	—	325	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.25	UI

Table 42. Memory Output Clock Jitter Specification for Stratix V Devices (1), (Part 2 of 2) (2), (3)

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
PHY Clock	Clock period jitter	$t_{JIT(per)}$	–25	25	–25	25	–30	30	–35	35	ps
	Cycle-to-cycle period jitter	$t_{JIT(cc)}$	–50	50	–50	50	–60	60	–70	70	ps
	Duty cycle jitter	$t_{JIT(duty)}$	–37.5	37.5	–37.5	37.5	–45	45	–56	56	ps

Notes to Table 42:

(1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.

(2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.

(3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

OCT Calibration Block Specifications

Table 43 lists the OCT calibration block specifications for Stratix V devices.

Table 43. OCT Calibration Block Specifications for Stratix V Devices

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
T_{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT R_S/R_T calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
T_{RS_RT}	Time required between the `dyn_term_ctrl` and `oe` signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (Figure 10)	—	2.5	—	ns

Figure 10 shows the timing diagram for the `oe` and `dyn_term_ctrl` signals.

Figure 10. Timing Diagram for oe and dyn_term_ctrl Signals

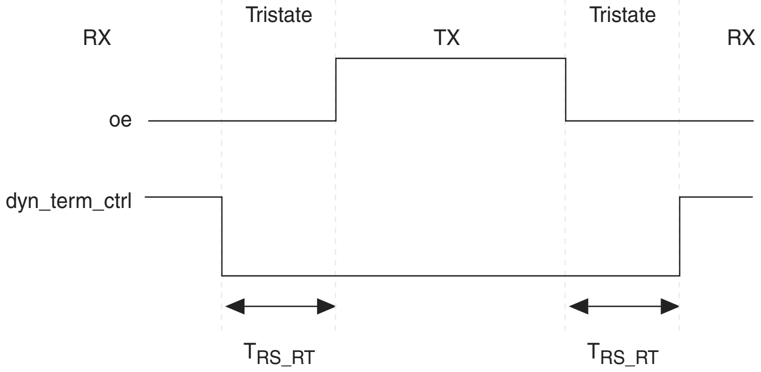


Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t_{JPH}	JTAG port hold time	5	—	ns
t_{JPCO}	JTAG port clock to output	—	11 (1)	ns
t_{JPZX}	JTAG port high impedance to valid output	—	14 (1)	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	14 (1)	ns

Notes to Table 46:

(1) A 1 ns adder is required for each V_{CCIO} voltage step down from 3.0 V. For example, t_{JPCO} = 12 ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

(2) The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

Raw Binary File Size

For the POR delay specification, refer to the "POR Delay Specification" section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices".

Table 47 lists the uncompressed raw binary file (**.rbf**) sizes for Stratix V devices.

Table 47. Uncompressed .rbf Sizes for Stratix V Devices

Family	Device	Package	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits) (4), (5)
Stratix V GX	5SGXA3	H35, F40, F35 (2)	213,798,880	562,392
		H29, F35 (3)	137,598,880	564,504
	5SGXA4	—	213,798,880	563,672
	5SGXA5	—	269,979,008	562,392
	5SGXA7	—	269,979,008	562,392
	5SGXA9	—	342,742,976	700,888
	5SGXAB	—	342,742,976	700,888
	5SGXB5	—	270,528,640	584,344
	5SGXB6	—	270,528,640	584,344
	5SGXB9	—	342,742,976	700,888
	5SGXBB	—	342,742,976	700,888
Stratix V GT	5SGTC5	—	269,979,008	562,392
	5SGTC7	—	269,979,008	562,392
Stratix V GS	5SGSD3	—	137,598,880	564,504
	5SGSD4	F1517	213,798,880	563,672
		—	137,598,880	564,504
	5SGSD5	—	213,798,880	563,672
	5SGSD6	—	293,441,888	565,528
	5SGSD8	—	293,441,888	565,528

Table 48. Minimum Configuration Time Estimation for Stratix V Devices

Variant	Member Code	Active Serial (1)			Fast Passive Parallel (2)		
		Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
GS	D3	4	100	0.344	32	100	0.043
	D4	4	100	0.534	32	100	0.067
		4	100	0.344	32	100	0.043
	D5	4	100	0.534	32	100	0.067
	D6	4	100	0.741	32	100	0.093
	D8	4	100	0.741	32	100	0.093
E	E9	4	100	0.857	32	100	0.107
	EB	4	100	0.857	32	100	0.107

Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

Fast Passive Parallel Configuration Timing

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

DCLK-to-DATA[] Ratio for FPP Configuration

FPP configuration requires a different `DCLK`-to-`DATA[]` ratio when you enable the design security, decompression, or both features. Table 49 lists the `DCLK`-to-`DATA[]` ratio for each combination.

Table 49. DCLK-to-DATA[] Ratio (1) (Part 1 of 2)

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×8	Disabled	Disabled	1
	Disabled	Enabled	1
	Enabled	Disabled	2
	Enabled	Enabled	2
FPP ×16	Disabled	Disabled	1
	Disabled	Enabled	2
	Enabled	Disabled	4
	Enabled	Enabled	4

Table 49. DCLK-to-DATA[] Ratio *(1)* **(Part 2 of 2)**

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×32	Disabled	Disabled	1
	Disabled	Enabled	4
	Enabled	Disabled	8
	Enabled	Enabled	8

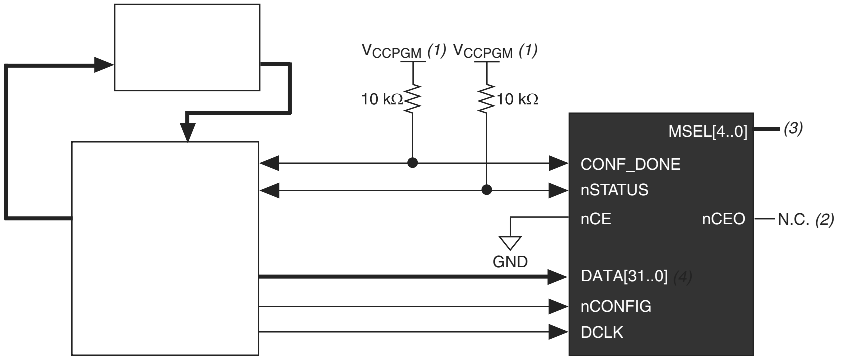
Note to Table 49:

(1) Depending on the `DCLK`-to-`DATA[]` ratio, the host must send a `DCLK` frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the `DCLK`-to-`DATA[]` ratio is 2, the `DCLK` frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.

If the `DCLK`-to-`DATA[]` ratio is greater than 1, at the end of configuration, you can only stop the `DCLK` (`DCLK`-to-`DATA[]` ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host



Notes to Figure 11:

(1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM}.

(2) You can leave the `nCEO` pin unconnected or use it as a user I/O pin when it does not feed another device's `nCE` pin.

(3) The `MSEL` pin settings vary for different data width, configuration voltage standards, and POR delay. To connect `MSEL`, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

(4) If you use FPP ×8, use `DATA[7..0]`. If you use FPP ×16, use `DATA[15..0]`.

Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the `DCLK`-to-`DATA[]` ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices *(1)*

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	`nCONFIG` low to `CONF_DONE` low	—	600	ns
t_{CF2ST0}	`nCONFIG` low to `nSTATUS` low	—	600	ns
t_{CFG}	`nCONFIG` low pulse width	2	—	µs
t_{STATUS}	`nSTATUS` low pulse width	268	1,506 *(2)*	µs
t_{CF2ST1}	`nCONFIG` high to `nSTATUS` high	—	1,506 *(3)*	µs
t_{CF2CK} *(6)*	`nCONFIG` high to first rising edge on `DCLK`	1,506	—	µs
t_{ST2CK} *(6)*	`nSTATUS` high to first rising edge of `DCLK`	2	—	µs
t_{DSU}	`DATA[]` setup time before rising edge on `DCLK`	5.5	—	ns
t_{DH}	`DATA[]` hold time after rising edge on `DCLK`	0	—	ns
t_{CH}	`DCLK` high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	`DCLK` low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	`DCLK` period	$1/f_{MAX}$	—	s
f_{MAX}	`DCLK` frequency (FPP ×8/×16)	—	125	MHz
	`DCLK` frequency (FPP ×32)	—	100	MHz
t_{CD2UM}	`CONF_DONE` high to user mode *(4)*	175	437	µs
t_{CD2CU}	`CONF_DONE` high to `CLKUSR` enabled	4 × maximum `DCLK` period	—	—
t_{CD2UMC}	`CONF_DONE` high to user mode with `CLKUSR` option on	t_{CD2CU} + (8576 × `CLKUSR` period) *(5)*	—	—

Notes to Table 50:

(1) Use these timing parameters when the decompression and design security features are disabled.

(2) This value is applicable if you do not delay configuration by extending the `nCONFIG` or `nSTATUS` low pulse width.

(3) This value is applicable if you do not delay configuration by externally holding the `nSTATUS` low.

(4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

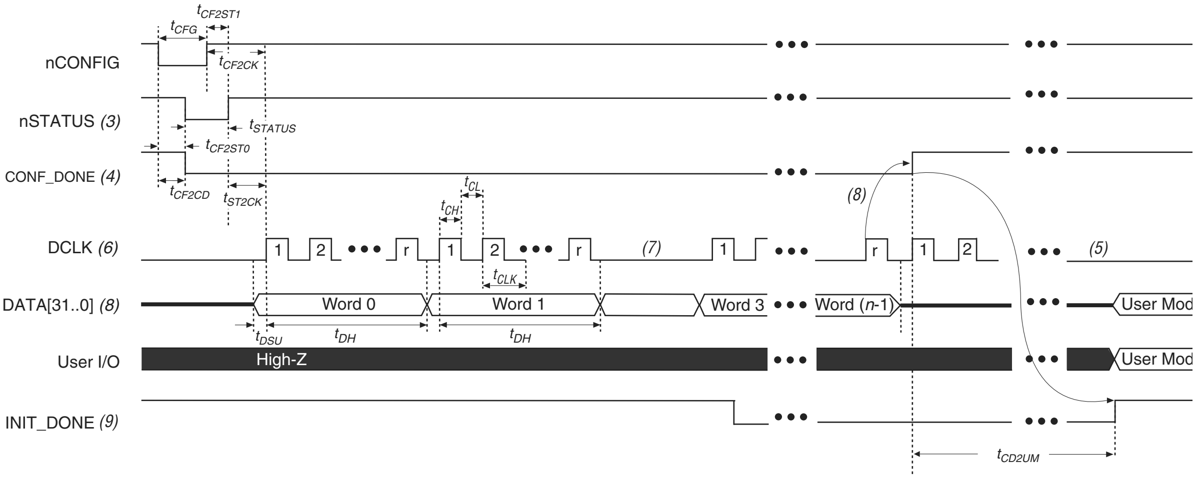
(5) To enable the `CLKUSR` pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

(6) If `nSTATUS` is monitored, follow the t_{ST2CK} specification. If `nSTATUS` is not monitored, follow the t_{CF2CK} specification.

FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the `DCLK`-to-`DATA[]` ratio is more than 1.

Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 *(1), (2)*



Notes to Figure 13:

(1) Use this timing waveform and parameters when the `DCLK`-to-`DATA[]` ratio is >1. To find out the `DCLK`-to-`DATA[]` ratio for your system, refer to Table 49 on page 55.

(2) The beginning of this waveform shows the device in user mode. In user mode, `nCONFIG`, `nSTATUS`, and `CONF_DONE` are at logic high levels. When `nCONFIG` is pulled low, a reconfiguration cycle begins.

(3) After power-up, the Stratix V device holds `nSTATUS` low for the time as specified by the POR delay.

(4) After power-up, before and during configuration, `CONF_DONE` is low.

(5) Do not leave `DCLK` floating after configuration. You can drive it high or low, whichever is more convenient.

(6) “r” denotes the `DCLK`-to-`DATA[]` ratio. For the `DCLK`-to-`DATA[]` ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.

(7) If needed, pause `DCLK` by holding it low. When `DCLK` restarts, the external host must provide data on the `DATA[31..0]` pins prior to sending the first `DCLK` rising edge.

(8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. `CONF_DONE` is released high after the Stratix V device receives all the configuration data successfully. After `CONF_DONE` goes high, send two additional falling edges on `DCLK` to begin initialization and enter user mode.

(9) After the option bit to enable the `INIT_DONE` pin is configured into the device, the `INIT_DONE` goes low.

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is more than 1.

Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1 *(1)*

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	µs
t_{STATUS}	nSTATUS low pulse width	268	1,506 *(2)*	µs
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 *(2)*	µs
t_{CF2CK} *(5)*	nCONFIG high to first rising edge on DCLK	1,506	—	µs
t_{ST2CK} *(5)*	nSTATUS high to first rising edge of DCLK	2	—	µs
t_{DSU}	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA[] hold time after rising edge on DCLK	$N–1/f_{DCLK}$ *(5)*	—	s
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP ×8/×16)	—	125	MHz
	DCLK frequency (FPP ×32)	—	100	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	CONF_DONE high to user mode *(3)*	175	437	µs
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (8576 × CLKUSR period) *(4)*	—	—

Notes to Table 51:

(1) Use these timing parameters when you use the decompression and design security features.

(2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.

(4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

(5) N is the DCLK-to-DATA ratio and f_{DCLK} is the DCLK frequency the system is operating.

(6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.